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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	STM8
Core Size	8-Bit
Speed	24MHz
Connectivity	I²C, IrDA, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	52
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	1.5K x 8
RAM Size	6K x 8
Voltage - Supply (Vcc/Vdd)	2.95V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	-
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8s207r8t6

2 Description

The STM8S20xxx performance line 8-bit microcontrollers offer from 32 to 128 Kbytes Flash program memory. They are referred to as high-density devices in the STM8S microcontroller family reference manual.

All STM8S20xxx devices provide the following benefits: reduced system cost, performance robustness, short development cycles, and product longevity.

The system cost is reduced thanks to an integrated true data EEPROM for up to 300 k write/erase cycles and a high system integration level with internal clock oscillators, watchdog, and brown-out reset.

Device performance is ensured by 20 MIPS at 24 MHz CPU clock frequency and enhanced characteristics which include robust I/O, independent watchdogs (with a separate clock source), and a clock security system.

Short development cycles are guaranteed due to application scalability across a common family product architecture with compatible pinout, memory map and modular peripherals. Full documentation is offered with a wide choice of development tools.

Product longevity is ensured in the STM8S family thanks to their advanced core which is made in a state-of-the art technology for applications with 2.95 V to 5.5 V operating supply.

4 Product overview

The following section intends to give an overview of the basic features of the STM8S20xxx functional modules and peripherals.

For more detailed information please refer to the corresponding family reference manual (RM0016).

4.1 Central processing unit STM8

The 8-bit STM8 core is designed for code efficiency and performance.

It contains 6 internal registers which are directly addressable in each execution context, 20 addressing modes including indexed indirect and relative addressing and 80 instructions.

Architecture and registers

- Harvard architecture
- 3-stage pipeline
- 32-bit wide program memory bus - single cycle fetching for most instructions
- X and Y 16-bit index registers - enabling indexed addressing modes with or without offset and read-modify-write type data manipulations
- 8-bit accumulator
- 24-bit program counter - 16-Mbyte linear memory space
- 16-bit stack pointer - access to a 64 K-level stack
- 8-bit condition code register - 7 condition flags for the result of the last instruction

Addressing

- 20 addressing modes
- Indexed indirect addressing mode for look-up tables located anywhere in the address space
- Stack pointer relative addressing mode for local variables and parameter passing

Instruction set

- 80 instructions with 2-byte average instruction size
- Standard data movement and logic/arithmetic functions
- 8-bit by 8-bit multiplication
- 16-bit by 8-bit and 16-bit by 16-bit division
- Bit manipulation
- Data transfer between stack and accumulator (push/pop) with direct stack access
- Data transfer using the X and Y registers or direct memory-to-memory transfers

4.2 Single wire interface module (SWIM) and debug module (DM)

The single wire interface module and debug module permits non-intrusive, real-time in-circuit debugging and fast memory programming.

SWIM

Single wire interface module for direct access to the debug module and memory programming. The interface can be activated in all device operation modes. The maximum data transmission speed is 145 bytes/ms.

Debug module

The non-intrusive debugging module features a performance close to a full-featured emulator. Beside memory and peripherals, also CPU operation can be monitored in real-time by means of shadow registers.

- R/W to RAM and peripheral registers in real-time
- R/W access to all resources by stalling the CPU
- Breakpoints on all program-memory instructions (software breakpoints)
- Two advanced breakpoints, 23 predefined configurations

4.3 Interrupt controller

- Nested interrupts with three software priority levels
- 32 interrupt vectors with hardware priority
- Up to 37 external interrupts on six vectors including TLI
- Trap and reset interrupts

4.4 Flash program and data EEPROM memory

- Up to 128 Kbytes of high density Flash program single voltage Flash memory
- Up to 2K bytes true data EEPROM
- Read while write: Writing in data memory possible while executing code in program memory.
- User option byte area

Write protection (WP)

Write protection of Flash program memory and data EEPROM is provided to avoid unintentional overwriting of memory that could result from a user software malfunction.

There are two levels of write protection. The first level is known as MASS (memory access security system). MASS is always enabled and protects the main Flash program memory, data EEPROM and option bytes.

To perform in-application programming (IAP), this write protection can be removed by writing a MASS key sequence in a control register. This allows the application to write to data EEPROM, modify the contents of main program memory or the device option bytes.

A second level of write protection, can be enabled to further protect a specific area of memory known as UBC (user boot code). Refer to *Figure 2*.

4.12 TIM4 - 8-bit basic timer

- 8-bit autoreload, adjustable prescaler ratio to any power of 2 from 1 to 128
- Clock source: CPU clock
- Interrupt source: 1 x overflow/update

Table 4. TIM timer features

Timer	Counter size (bits)	Prescaler	Counting mode	CAPCOM channels	Complem. outputs	Ext. trigger	Timer synchr-onization/ chaining
TIM1	16	Any integer from 1 to 65536	Up/down	4	3	Yes	No
TIM2	16	Any power of 2 from 1 to 32768	Up	3	0	No	
TIM3	16	Any power of 2 from 1 to 32768	Up	2	0	No	
TIM4	8	Any power of 2 from 1 to 128	Up	0	0	No	

4.13 Analog-to-digital converter (ADC2)

STM8S20xxx performance line products contain a 10-bit successive approximation A/D converter (ADC2) with up to 16 multiplexed input channels and the following main features:

- Input voltage range: 0 to V_{DDA}
- Dedicated voltage reference (VREF) pins available on 80 and 64-pin devices
- Conversion time: 14 clock cycles
- Single and continuous modes
- External trigger input
- Trigger from TIM1 TRGO
- End of conversion (EOC) interrupt

4.14 Communication interfaces

The following communication interfaces are implemented:

- UART1: Full feature UART, SPI emulation, LIN2.1 master capability, Smartcard mode, IrDA mode, single wire mode.
- UART3: Full feature UART, LIN2.1 master/slave capability
- SPI: Full and half-duplex, 10 Mbit/s
- I^2C: Up to 400 Kbit/s
- beCAN (rev. 2.0A,B) - 3 Tx mailboxes - up to 1 Mbit/s

remap) option bits. Refer to *Section 8: Option bytes on page 47*. When the remapping option is active, the default alternate function is no longer available.

To use an alternate function, the corresponding peripheral must be enabled in the peripheral registers.

Alternate function remapping does not effect GPIO capabilities of the I/O ports (see the GPIO section of the family reference manual, RM0016).

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 50CC	CLK	CLK_HSITRIMR	HSI clock calibration trimming register	0x00
0x00 50CD		CLK_SWIMCCR	SWIM clock control register	0bXXXX XXX0
0x00 50CE to 0x00 50D0	Reserved area (3 bytes)			
0x00 50D1	WWDG	WWDG_CR	WWDG control register	0x7F
0x00 50D2		WWDG_WR	WWDR window register	0x7F
0x00 50D3 to 0x00 50DF	Reserved area (13 bytes)			
0x00 50E0	IWDG	IWDG_KR	IWDG key register	0xXX(2)
0x00 50E1		IWDG_PR	IWDG prescaler register	0x00
0x00 50E2		IWDG_RLR	IWDG reload register	0xFF
0x00 50E3 to 0x00 50EF	Reserved area (13 bytes)			
0x00 50F0	AWU	AWU_CSR1	AWU control/status register 1	0x00
0x00 50F1		AWU_APR	AWU asynchronous prescaler buffer register	0x3F
0x00 50F2		AWU_TBR	AWU timebase selection register	0x00
0x00 50F3	BEEP	BEEP_CSR	BEEP control/status register	0x1F
0x00 50F4 to 0x00 50FF	Reserved area (12 bytes)			
0x00 5200	SPI	SPI_CR1	SPI control register 1	0x00
0x00 5201		SPI_CR2	SPI control register 2	0x00
0x00 5202		SPI_ICR	SPI interrupt control register	0x00
0x00 5203		SPI_SR	SPI status register	0x02
0x00 5204		SPI_DR	SPI data register	0x00
0x00 5205		SPI_CRCPR	SPI CRC polynomial register	0x07
0x00 5206		SPI_RXCRCR	SPI Rx CRC register	0xFF
0x00 5207		SPI_TXCRCR	SPI Tx CRC register	0xFF
0x00 5208 to 0x00 520F	Reserved area (8 bytes)			
0x00 5210	I^2C	I2C_CR1	I^2C control register 1	0x00
0x00 5211		I2C_CR2	I^2C control register 2	0x00
0x00 5212		I2C_FREQR	I^2C frequency register	0x00
0x00 5213		I2C_OARL	I^2C own address register low	0x00
0x00 5214		I2C_OARH	I^2C own address register high	0x00
0x00 5215		Reserved		

7 Interrupt vector mapping

Table 11. Interrupt mapping

IRQ no.	Source block	Description	Wakeup from Halt mode	Wakeup from Active-halt mode	Vector address
	RESET	Reset	Yes	Yes	0x00 8000
	TRAP	Software interrupt	-	-	0x00 8004
0	TLI	External top level interrupt	-	-	0x00 8008
1	AWU	Auto wake up from halt	-	Yes	0x00 800C
2	CLK	Clock controller	-	-	0x00 8010
3	EXTI0	Port A external interrupts	Yes(1)	Yes(1)	0x00 8014
4	EXTI1	Port B external interrupts	Yes	Yes	0x00 8018
5	EXTI2	Port C external interrupts	Yes	Yes	0x00 801C
6	EXTI3	Port D external interrupts	Yes	Yes	0x00 8020
7	EXTI4	Port E external interrupts	Yes	Yes	0x00 8024
8	beCAN	beCAN RX interrupt	Yes	Yes	0x00 8028
9	beCAN	beCAN TX/ER/SC interrupt	-	-	0x00 802C
10	SPI	End of transfer	Yes	Yes	0x00 8030
11	TIM1	TIM1 update/overflow/underflow/ trigger/break	-	-	0x00 8034
12	TIM1	TIM1 capture/compare	-	-	0x00 8038
13	TIM2	TIM2 update /overflow	-	-	0x00 803C
14	TIM2	TIM2 capture/compare	-	-	0x00 8040
15	TIM3	Update/overflow	-	-	0x00 8044
16	TIM3	Capture/compare	-	-	0x00 8048
17	UART1	Tx complete	-	-	0x00 804C
18	UART1	Receive register DATA FULL	-	-	0x00 8050
19	I^2C	I^2C interrupt	Yes	Yes	0x00 8054
20	UART3	Tx complete	-	-	0x00 8058
21	UART3	Receive register DATA FULL	-	-	0x00 805C
22	ADC2	ADC2 end of conversion	-	-	0x00 8060
23	TIM4	TIM4 update/overflow	-	-	0x00 8064
24	Flash	EOP/WR_PG_DIS	-	-	0x00 8068
Reserved					0x00 806C to 0x00 807C

1. Except PA1

10 Electrical characteristics

10.1 Parameter conditions

Unless otherwise specified, all voltages are referred to V_{SS}.

10.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at T_A = 25 °C and $T_A = T_{Amax}$ (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes and are not tested in production. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation (mean ± 3 Σ).

10.1.2 Typical values

Unless otherwise specified, typical data are based on T_A = 25 °C, V_{DD} = 5 V. They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated (mean ± 2 Σ).

10.1.3 Typical curves

Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

10.1.4 Typical current consumption

For typical current consumption measurements, V_{DD}, V_{DDIO} and V_{DDA} are connected together in the configuration shown in *Figure 9*.

Figure 9. Supply current measurement conditions

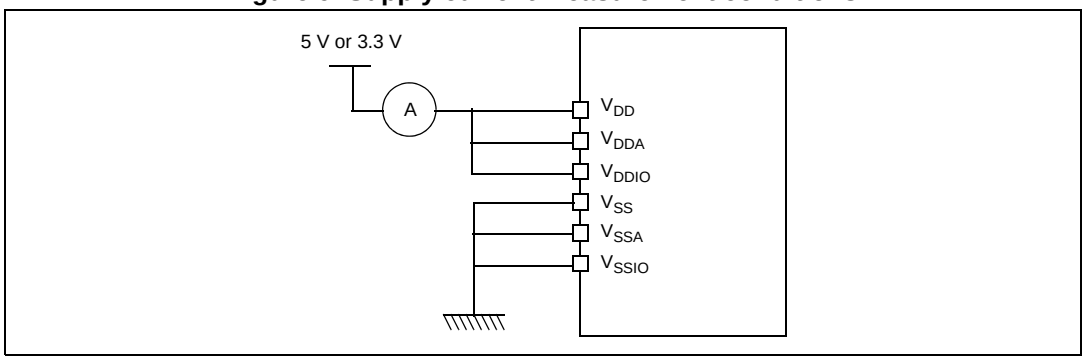


Table 21. Total current consumption with code execution in run mode at V_{DD} = 3.3 V

Symbol	Parameter	Conditions		Typ	Max(1)	Unit
$I_{DD(RUN)}$	Supply current in run mode, code executed from RAM	$f_{CPU} = f_{MASTER}$ = 24 MHz, $T_A \leq$ 105 °C	HSE crystal osc. (24 MHz)	4.0		mA
			HSE user ext. clock (24 MHz)	3.7	7.3	
		$f_{CPU} = f_{MASTER}$ = 16 MHz	HSE crystal osc. (16 MHz)	2.9		
			HSE user ext. clock (16 MHz)	2.7	5.8	
			HSI RC osc. (16 MHz)	2.5	3.4	
		$f_{CPU} = f_{MASTER}/128$ = 125 kHz	HSE user ext. clock (16 MHz)	1.2	4.1	
			HSI RC osc. (16 MHz)	1.0	1.3	
		$f_{CPU} = f_{MASTER}/128$ = 15.625 kHz	HSI RC osc. (16MHz/8)	0.55		
		$f_{CPU} = f_{MASTER}$ = 128 kHz	LSI RC osc. (128 kHz)	0.45		
	Supply current in run mode, code executed from Flash	$f_{CPU} = f_{MASTER}$ = 24 MHz, $T_A \leq$ 105 °C	HSE crystal osc. (24 MHz)	11.0		
			HSE user ext. clock (24 MHz)	10.8	18.0	
		$f_{CPU} = f_{MASTER}$ = 16 MHz	HSE crystal osc. (16 MHz)	8.4		
			HSE user ext. clock (16 MHz)	8.2	15.2	
			HSI RC osc. (16 MHz)	8.1	13.2	
		$f_{CPU} = f_{MASTER}$ = 2 MHz.	HSI RC osc. (16 MHz/8)(2)	1.5		
		$f_{CPU} = f_{MASTER}/128$ = 125 kHz	HSI RC osc. (16 MHz)	1.1		
		$f_{CPU} = f_{MASTER}/128$ = 15.625 kHz	HSI RC osc. (16 MHz/8)	0.6		
		$f_{CPU} = f_{MASTER}$ = 128 kHz	LSI RC osc. (128 kHz)	0.55		

1. Data based on characterization results, not tested in production.
2. Default clock configuration.

10.3.4 Internal clock sources and timing characteristics

Subject to general operating conditions for V_{DD} and T_A. f_{HSE}

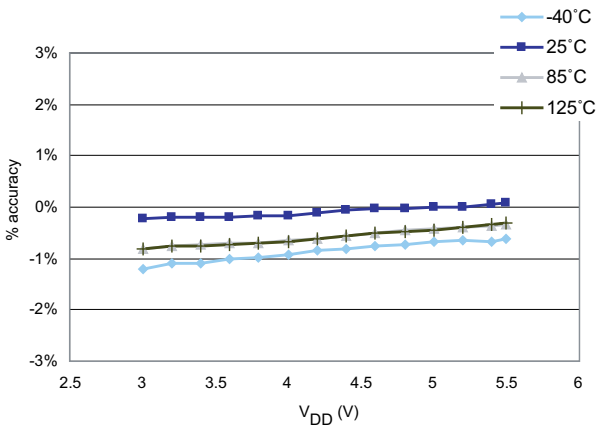
High speed internal RC oscillator (HSI)

Table 33. HSI oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSI}	Frequency			16		MHz
ACC_{HSI}	Accuracy of HSI oscillator	Trimmed by the CLK_HSITRIMR register for given V_{DD} and T_A conditions	-1.0(1)		1.0	%
	Accuracy of HSI oscillator (factory calibrated)	V_{DD} = 5 V, T_A = 25 °C	-1.5		1.5	
		V_{DD} = 5 V, 25 °C ≤ T_A ≤ 85 °C	-2.2		2.2	
		2.95 V ≤ V_{DD} ≤ 5.5 V, -40 °C ≤ T_A ≤ 125 °C	-3.0(2)		3.0(2)	
$t_{su(HSI)}$	HSI oscillator wakeup time including calibration				1.0(1)	µs
$I_{DD(HSI)}$	HSI oscillator power consumption			170	250(2)	µA

1. Guaranteed by design, not tested in production.
2. Data based on characterization results, not tested in production

Figure 18. Typical HSI frequency variation vs V_{DD} at 4 temperatures



Low speed internal RC oscillator (LSI)

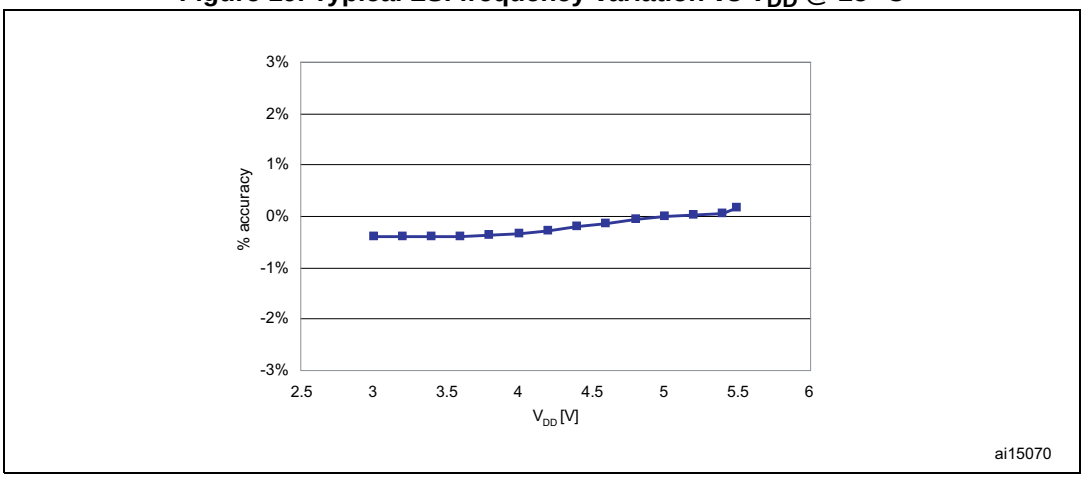
Subject to general operating conditions for V_{DD} and T_A.

Table 34. LSI oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{LSI}	Frequency		110	128	146	kHz
$t_{su(LSI)}$	LSI oscillator wakeup time				7(1)	µs
$I_{DD(LSI)}$	LSI oscillator power consumption			5		µA

1. Guaranteed by design, not tested in production.

Figure 19. Typical LSI frequency variation vs V_{DD} @ 25 °C



10.3.5 Memory characteristics

RAM and hardware registers

Table 35. RAM and hardware registers

Symbol	Parameter	Conditions	Min	Unit
V_{RM}	Data retention mode(1)	Halt mode (or reset)	V_{IT-max}(2)	V

1. Minimum supply voltage without losing data stored in RAM (in halt mode or under reset) or in hardware registers (only in halt mode). Guaranteed by design, not tested in production.
2. Refer to *Table 19 on page 57* for the value of V_{IT-max}.

Flash program memory/data EEPROM memory

General conditions: T_A = -40 to 125 °C.

Table 36. Flash program memory/data EEPROM memory

Symbol	Parameter	Conditions	Min(1)	Typ	Max	Unit
V_{DD}	Operating voltage (all modes, execution/write/erase)	$f_{CPU} \leq$ 24 MHz	2.95		5.5	V
t_{prog}	Standard programming time (including erase) for byte/word/block (1 byte/4 bytes/128 bytes)			6	6.6	ms
	Fast programming time for 1 block (128 bytes)			3	3.3	ms
t_{erase}	Erase time for 1 block (128 bytes)			3	3.3	ms
N_{RW}	Erase/write cycles(2) (program memory)	T_A = 85 °C	10 k			cycles
	Erase/write cycles (data memory)(2)	T_A = 125 ° C	300 k	1M		
t_{RET}	Data retention (program memory) after 10 k erase/write cycles at T_A = 85 °C	T_{RET} = 55° C	20			years
	Data retention (data memory) after 10 k erase/write cycles at T_A = 85 °C	T_{RET} = 55° C	20			
	Data retention (data memory) after 300k erase/write cycles at T_A = 125 °C	T_{RET} = 85° C	1			
I_{DD}	Supply current (Flash programming or erasing for 1 to 128 bytes)			2		mA

1. Data based on characterization results, not tested in production.
2. The physical granularity of the memory is 4 bytes, so cycling is performed on 4 bytes even when a write/erase operation addresses a single byte.

Figure 27. Typ. V_{OL} @ V_{DD} = 5 V (high sink ports)

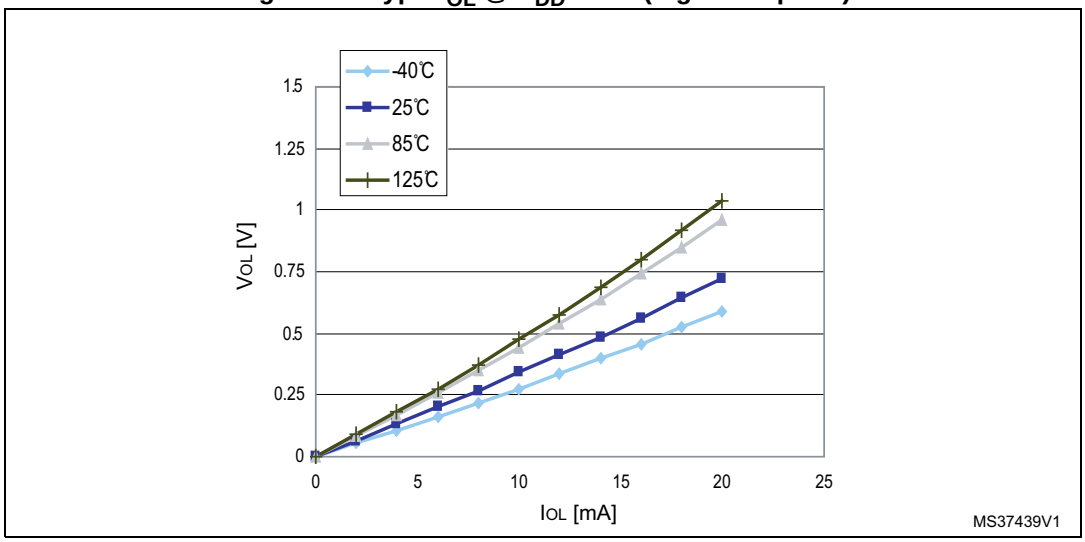


Figure 28. Typ. V_{OL} @ V_{DD} = 3.3 V (high sink ports)

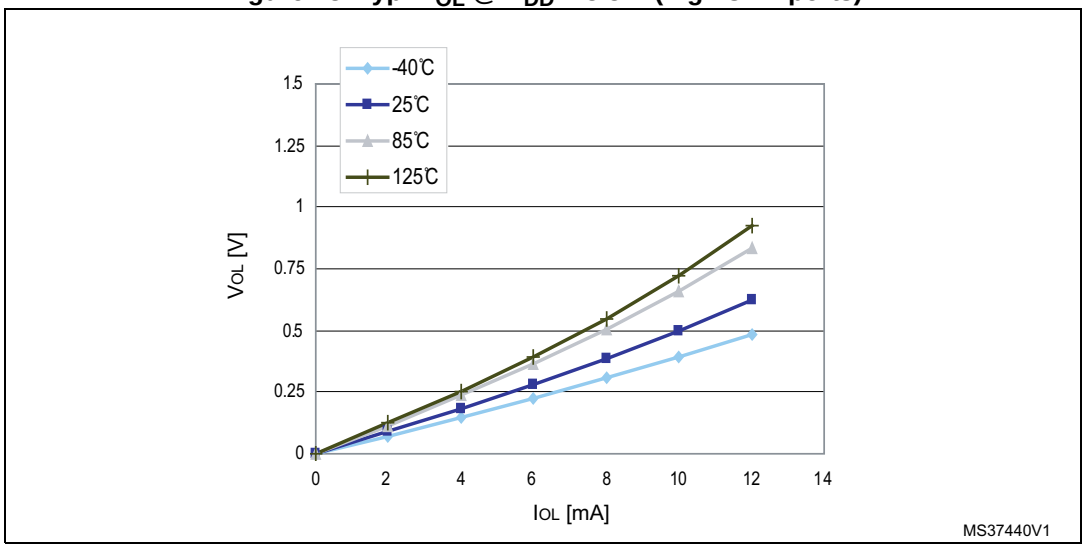


Figure 37. SPI timing diagram - slave mode and CPHA = 0

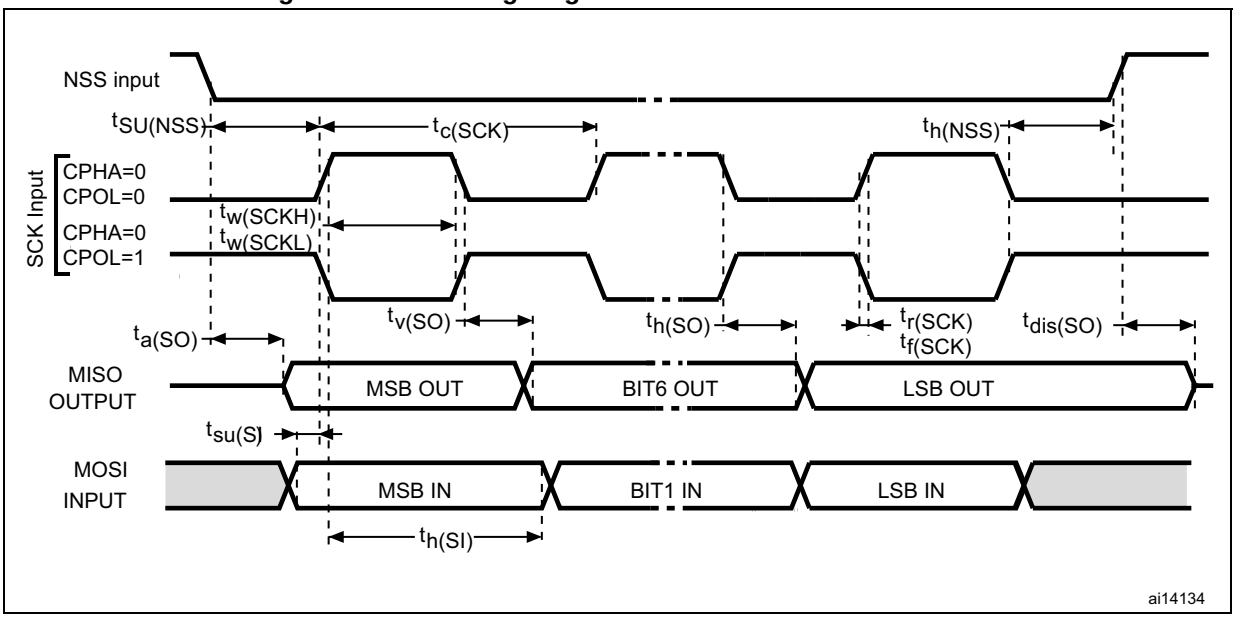
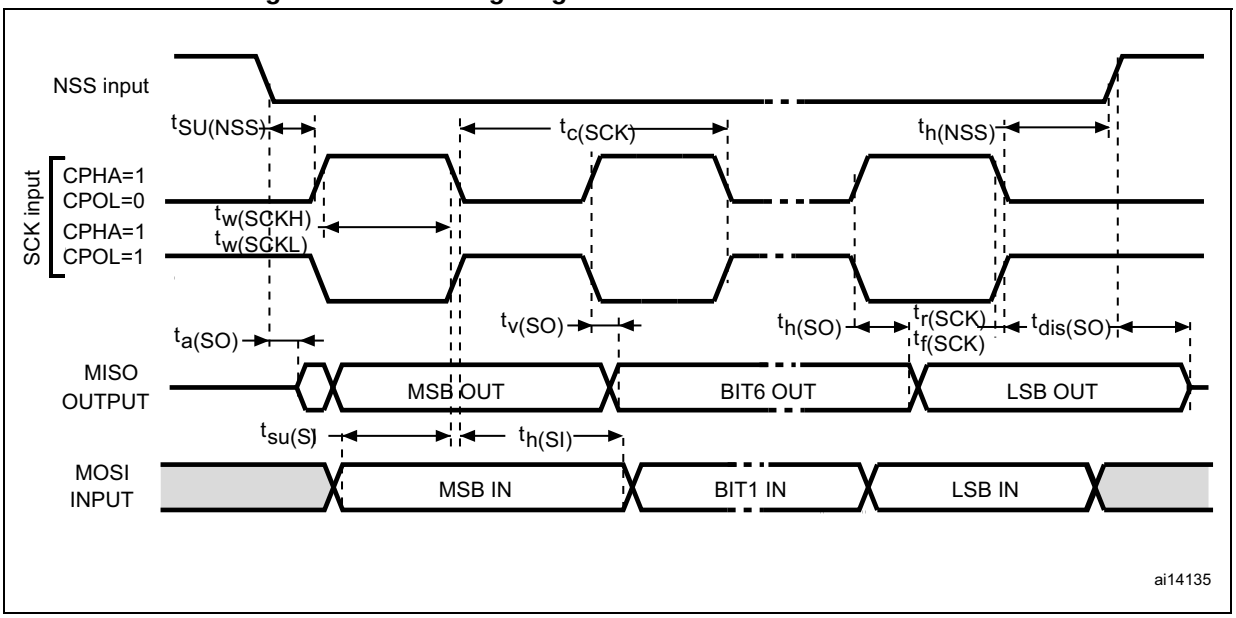


Figure 38. SPI timing diagram - slave mode and CPHA = 1(1)



1. Measurement points are done at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

10.3.9 I^2C interface characteristics

Table 43. I^2C characteristics

Symbol	Parameter	Standard mode I^2C		Fast mode I^2C(1)		Unit
		Min(2)	Max(2)	Min(2)	Max(2)	
$t_{w(SCLL)}$	SCL clock low time	4.7		1.3		µs
$t_{w(SCLH)}$	SCL clock high time	4.0		0.6		
$t_{su(SDA)}$	SDA setup time	250		100		ns
$t_{h(SDA)}$	SDA data hold time	0(3)		0(4)	900(3)	
$t_{r(SDA)}$ $t_{r(SCL)}$	SDA and SCL rise time		1000		300	
$t_{f(SDA)}$ $t_{f(SCL)}$	SDA and SCL fall time		300		300	
$t_{h(STA)}$	START condition hold time	4.0		0.6		µs
$t_{su(STA)}$	Repeated START condition setup time	4.7		0.6		
$t_{su(STO)}$	STOP condition setup time	4.0		0.6		µs
$t_{w(STO:STA)}$	STOP to START condition time (bus free)	4.7		1.3		µs
C_b	Capacitive load for each bus line		400		400	pF

1. f_{MASTER}, must be at least 8 MHz to achieve max fast I^2C speed (400kHz)
2. Data based on standard I^2C protocol requirement, not tested in production
3. The maximum hold time of the start condition has only to be met if the interface does not stretch the low time
4. The device must internally provide a hold time of at least 300 ns for the SDA signal in order to bridge the undefined region of the falling edge of SCL

Static latch-up

Two complementary static tests are required on 10 parts to assess the latch-up performance:

- A supply overvoltage (applied to each power supply pin)
- A current injection (applied to each input, output and configurable I/O pin) is performed on each sample.

This test conforms to the EIA/JESD 78 IC latch-up standard. For more details, refer to the application note AN1181.

Table 50. Electrical sensitivities

Symbol	Parameter	Conditions	Class(1)
LU	Static latch-up class	$T_A = 25$ °C	A
		$T_A = 85$ °C	A
		$T_A = 125$ °C	A

1. Class description: A Class is an STMicroelectronics internal specification. All its limits are higher than the JEDEC specifications, that means when a device belongs to class A it exceeds the JEDEC standard. B class strictly covers all the JEDEC criteria (international standard).

11.1.2 LQFP64 package information

Figure 46. LQFP64 - 64-pin 14 mm x 14 mm low-profile quad flat package outline

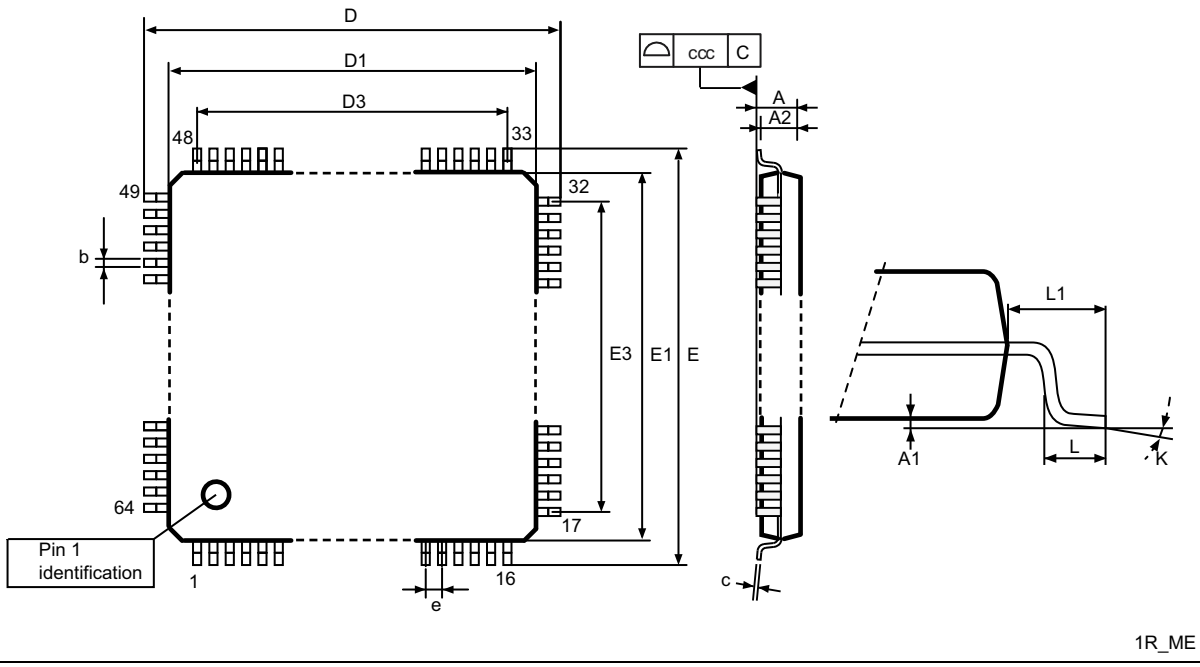


Table 52. LQFP64 - 64-pin, 14 x 14 mm low-profile quad flat package mechanical data

Symbol	mm			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A			1.600			0.0630
A1	0.050		0.150	0.0020		0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.300	0.370	0.450	0.0118	0.0146	0.0177
C	0.090		0.200	0.0035		0.0079
D	15.800	16.000	16.200	0.6220	0.6299	0.6378
D1	13.800	14.000	14.200	0.5433	0.5512	0.5591
D3		12.000			0.4724	
E	15.800	16.000	16.200	0.6220	0.6299	0.6378
E1	13.800	14.000	14.200	0.5433	0.5512	0.5591
E3		12.000			0.4724	
e		0.800			0.0315	
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1		1.000			0.0394	

11.2 Thermal characteristics

The maximum chip junction temperature (T_{Jmax}) must never exceed the values given in *Table 18: General operating conditions on page 56*.

The maximum chip-junction temperature, T_{Jmax}, in degrees Celsius, may be calculated using the following equation:

$T_{Jmax} = T_{Amax} + (P_{Dmax} \times \Theta_{JA})$

Where:

- T_{Amax} is the maximum ambient temperature in °C
- Θ_{JA} is the package junction-to-ambient thermal resistance in ° C/W
- P_{Dmax} is the sum of P_{INTmax} and $P_{I/Omax}$ ($P_{Dmax} = P_{INTmax} + P_{I/Omax}$)
- P_{INTmax} is the product of I_{DD} and V_{DD}, expressed in Watts. This is the maximum chip internal power.
- $P_{I/Omax}$ represents the maximum power dissipation on output pins, where: $P_{I/Omax} = \Sigma (V_{OL}*I_{OL}) + \Sigma((V_{DD}-V_{OH})*I_{OH})$, and taking account of the actual V_{OL}/I_{OL} and V_{OH}/I_{OH} of the I/Os at low and high level in the application.

Table 57. Thermal characteristics(1)

Symbol	Parameter	Value	Unit
Θ_{JA}	Thermal resistance junction-ambient LQFP 80 - 14 x 14 mm	38	°C/W
Θ_{JA}	Thermal resistance junction-ambient LQFP 64 - 14 x 14 mm	45	°C/W
Θ_{JA}	Thermal resistance junction-ambient LQFP 64 - 10 x 10 mm	46	°C/W
Θ_{JA}	Thermal resistance junction-ambient LQFP 48 - 7 x 7 mm	57	°C/W
Θ_{JA}	Thermal resistance junction-ambient LQFP 44 - 10 x 10 mm	54	°C/W
Θ_{JA}	Thermal resistance junction-ambient LQFP 32 - 7 x 7 mm	60	°C/W

1. Thermal resistances are based on JEDEC JESD51-2 with 4-layer PCB in a natural convection environment.

11.2.1 Reference document

JESD51-2 integrated circuits thermal test method environment conditions - natural convection (still air). Available from www.jedec.org.

Table 58. Document revision history (continued)

Date	Revision	Changes
18-Feb-2015	13	Updated: – *Figure 43: LQFP80 - 80-pin, 14 x 14 mm low-profile quad flat package outline* – *Table 51: LQFP80 - 80-pin, 14 x 14 mm low-profile quad flat package mechanical data* – *Figure 51: LQFP80 - 80-pin, 14 x 14 mm low-profile quad flat package mechanical data* – *Figure 47: LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package outline* – *Table 53: LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data* – *Figure 50: LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package outline* – *Table 54: LQFP48 - 48-pin, 7x 7 mm low-profile quad flat package mechanical* – *Figure 56: LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package outline* – *Table 56: LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package mechanical data* Added: – *Figure 44: LQFP80 recommended footprint* – *Figure 45: LQFP80 marking example (package top view)* – *Figure 48: LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat recommended footprint* – *Figure 49: LQFP64 marking example (package top view)* – *Figure 51: LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat recommended footprint* – *Figure 52: LQFP48 marking example (package top view)* – *Figure 54: LQFP44 - 44-pin, 10 x 10 mm low-profile quad flat recommended footprint* – *Figure 55: LQFP44 marking example (package top view)* – *Figure 57: LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat recommended footprint* – *Figure 58: LQFP32 marking example (package top view)*